

Issue Classification	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10764200	LEE ET AL.
	Examiner	Art Unit
	Wiehe, Nathan	3745

Wiehe, Nathan (Assistant Examiner)	<i>1/18/08</i> (Date)	<i>Edward K. Look</i> EDWARD K. LOOK	Total Claims Allowed: 15	
(Legal Instruments Examiner)	(Date)	SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 <i>1/18/08</i> (Primary Examiner) (Date)	O.G. Print Claim(s) 1	O.G. Print Figure 1